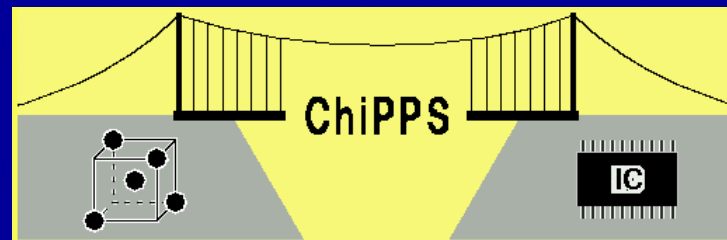


Building a bridge between *ab-initio* calculations and process simulation



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Thanks to:

E. Rubio, P. Castrillo, R. Pinacho,
L. Pelaz, J. Barbolla
University of Valladolid, Spain

G. Gilmer, C. Rafferty
Bell Labs Lucent Tech., USA

Outline

- The Problem: Complex Processing
- The Solution: Atomistic Kinetic Monte Carlo
- The Challenge: Obtaining the Parameters
- Looking Ahead: Genetic Algorithms, Neural Networks, ...



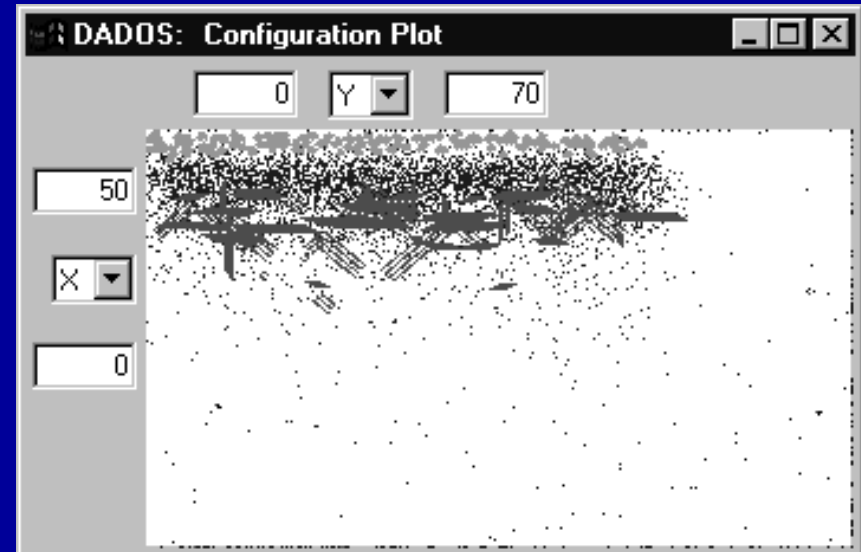
The Problem

Complex Materials Processing
Scenarios

The Problem:

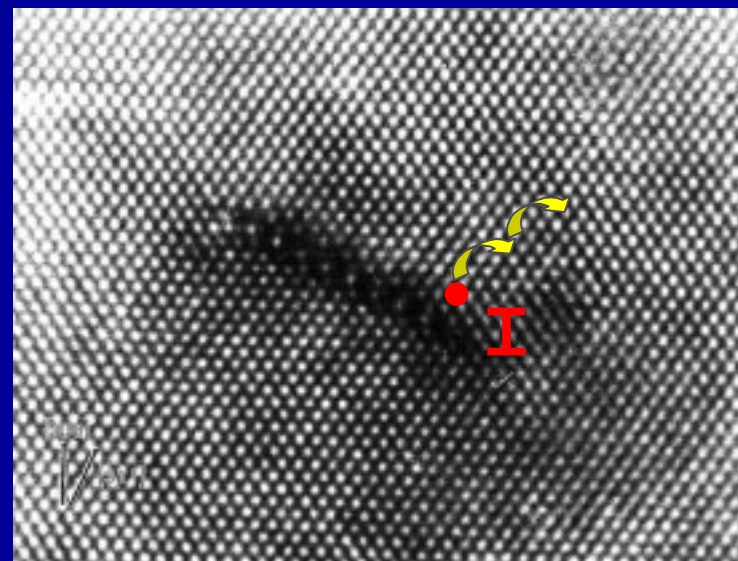
Complex Processing Scenarios

1. Many different species
(V, I, As, C, O, B, ...)
1. ... and interactions
(I-B, V-O, I-C-O, ...)
1. Highly non-equilibrium conditions
(Pair reactions, ...)
4. Extended defects
(voids, {311}'s, loops, ...)
 - Emission/Capture rates dependent on Size & Shape
5. Low thermal budget
(electrical activation?)
6. Ever smaller device dimensions
 - 2D: short channel effect
 - 3D: narrow channel effect
 - Local inhomogeneities (dopant discreteness)



The Problem: Complex Processing Scenarios

- Molecular Dynamics (MD) is most accurate, but limited to <1 nanosecond:
 - Follows all the atoms
 - 'Fixed' time step $\cong 10^{-15}$ s
- We use MD (off-line) to calculate the KMC event rates.





The Solution

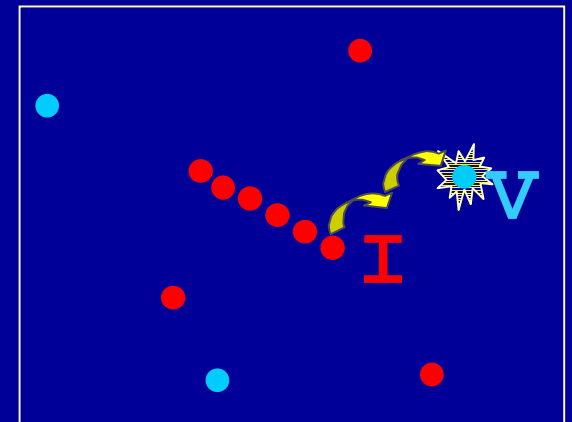
Atomistic Kinetic Monte Carlo
(KMC)

KMC vs. Molecular Dynamics

- Uses event rates obtained from DFT, classical MD or experiments
- KMC follows only the defect atoms
- Self-adjusts the timestep during the course of the simulation

Δt : ps ... hours

KMC simulates real processing times
using atomistic mechanisms



KMC vs. Continuum Models

Continuum

SOLVE:

$$dI/dt = D d^2I/dx^2 - R_{Bulk}$$

SOLVE:

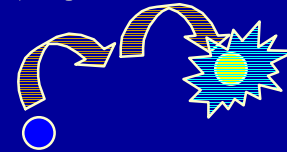
$$dI/dt = D d^2I/dx^2 - K_{IF} B_S I + K_{IR} B_I - R_{Bulk}$$

$$dB_I/dt = D dB_I^2/dx^2 + K_{BIF} B_S I - K_{BIR} B_I$$

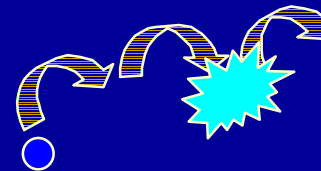
$$dB_S/dt = K_{SI} - K_{SI} B_S$$

computation time ↑↑↑

TO SIMULATE:



TO ADD NEW MECHANISM:



⇒ almost no additional
computation time

Atomistic

PROGRAM:

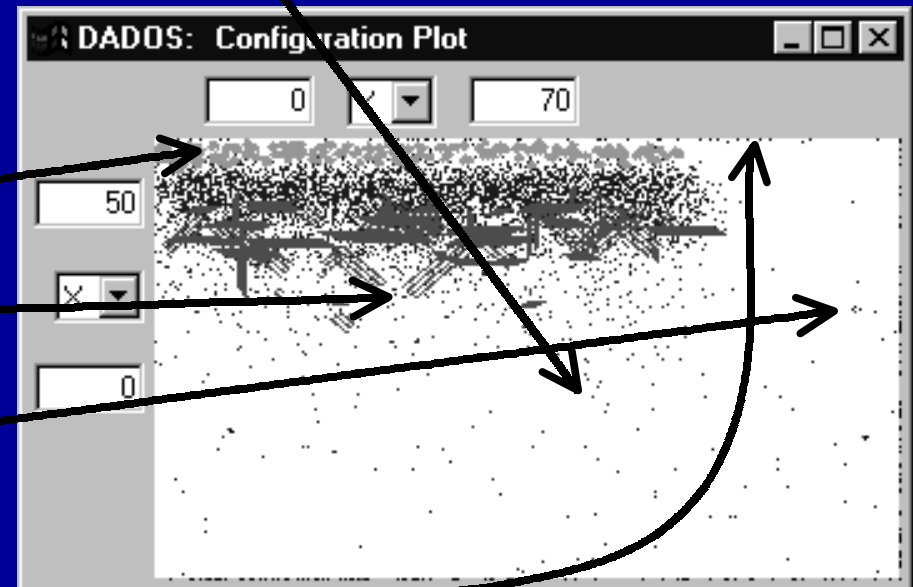
annihilate(I);
annihilate(V);

PROGRAM:

annihilate(I);
B_I annihilate(B_S);

KMC: Accurate description of Defects

- Point defects (V, I, B, As, ...)
- Extended defects (actual geometry)
 - Small clusters
 - V: Voids
 - I: {311}'s, Loops
 - Dopant clusters ($B_n I_m, \dots$)
- Surfaces



KMC: Easy definition of Defect Interactions

```
...
case Vacancy:
    switch ( neighbor )
    {
        case Vacancy:
            return new Cluster<Vacancy>;
        case Bi:
            neighbor->delete();
            this->delete();
            return new PointD<Boron>;
    }

```

...

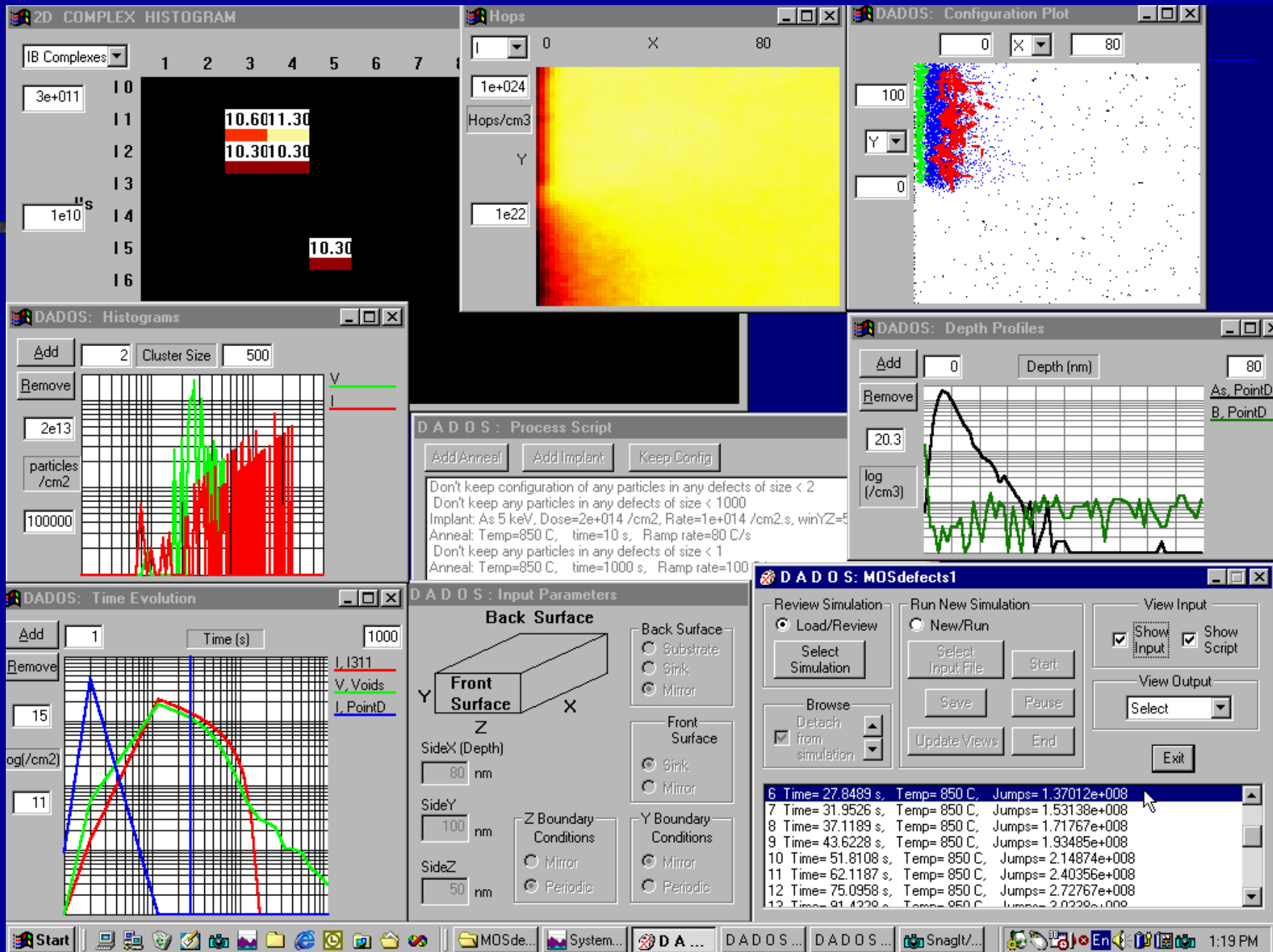
- Execution speed independent of number of interactions

The KMC core: The Event Scheduler

EXAMPLE:

	n	J_{rate} (jumps/s)	Total Jumps/s
V	2	1000	2000
I	5	10	50

- To simulate 1 second anneal we need to simulate 2050 Jumps
 $\Rightarrow \Delta t = 1/2050$ seconds per Jump
- We have to pick up V's and I's with a probability of 2000/2050 and 50/2050, respectively



KMC: Example 1

Local Inhomogeneities:

- Dopant Discreteness
- Clusters

Dopant Distribution Models

Continuum Models



Dopants: Discrete Random (?)



Possible Spatial correlation due to:

- Dopant charge states
- Clusters

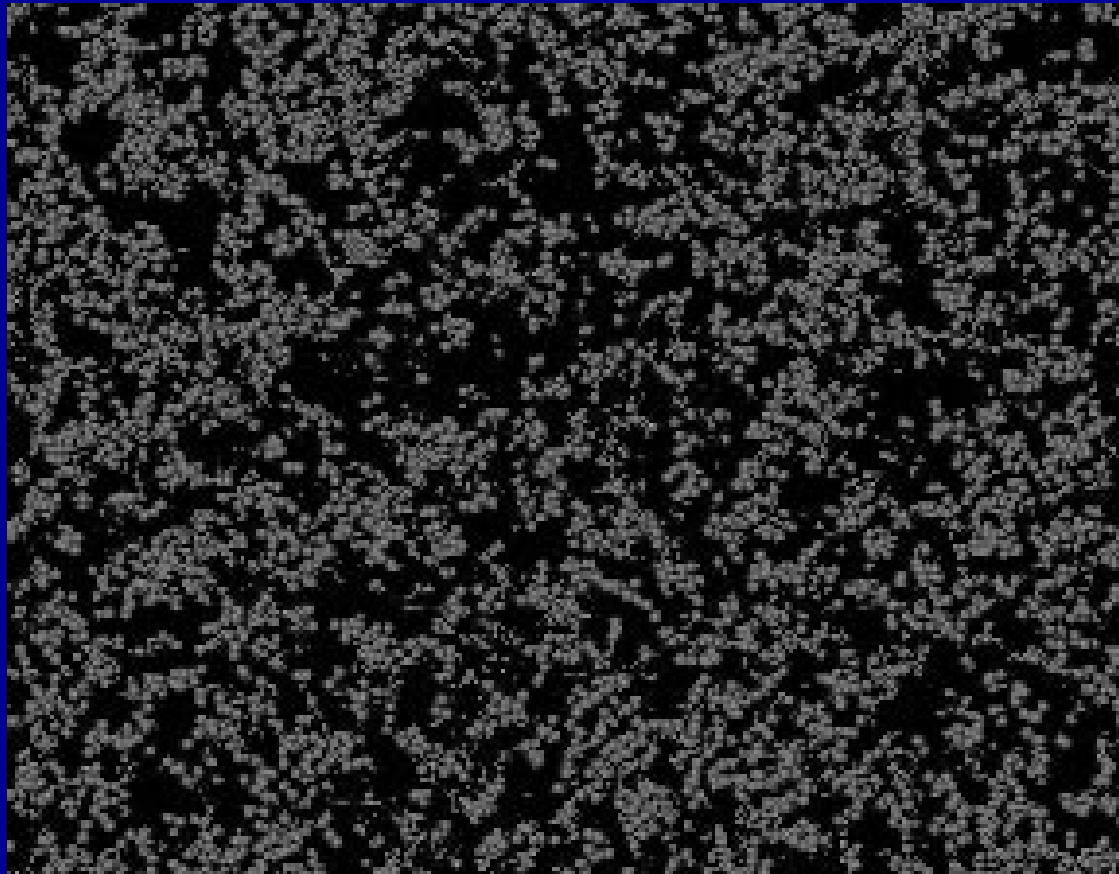
Dopants: Possible spatial correlation

Diffusion of charged point defects could give rise to spatial correlation (they cannot be arbitrarily close to each other).

In fact, similar effects have been shown to occur in the oxide charge distribution in MOS structures
⇒ change in the effective mobility.

F. Gamiz et al., Semic. Sci. & Technol, (1994)

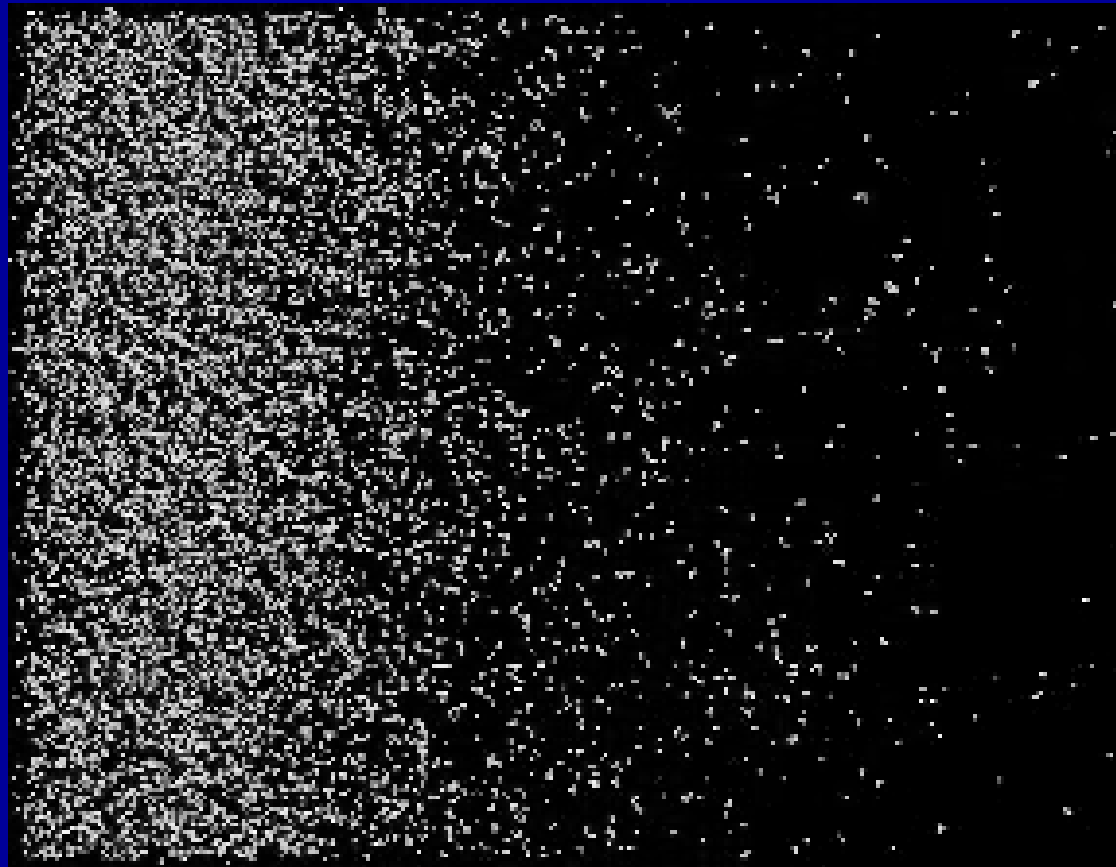
Local Inhomogeneities: Clusters



Front View

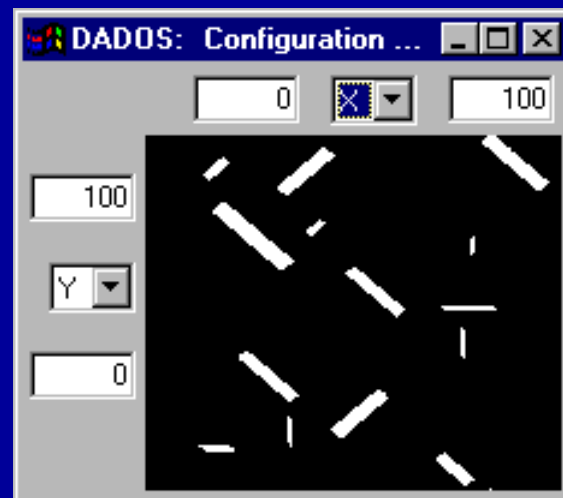
Local Inhomogeneities: Clusters

Front Surface

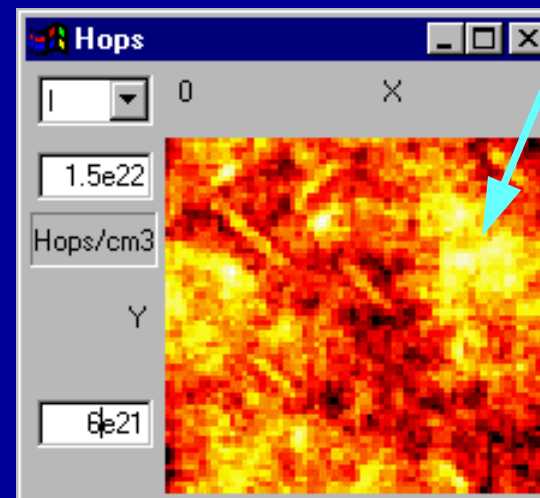


Cross-section

Local Inhomogeneities: Clusters



{311} defects



Interst. hops

High B diffusivity

KMC: Example 2

KMC used to validate
Simplifying Assumptions

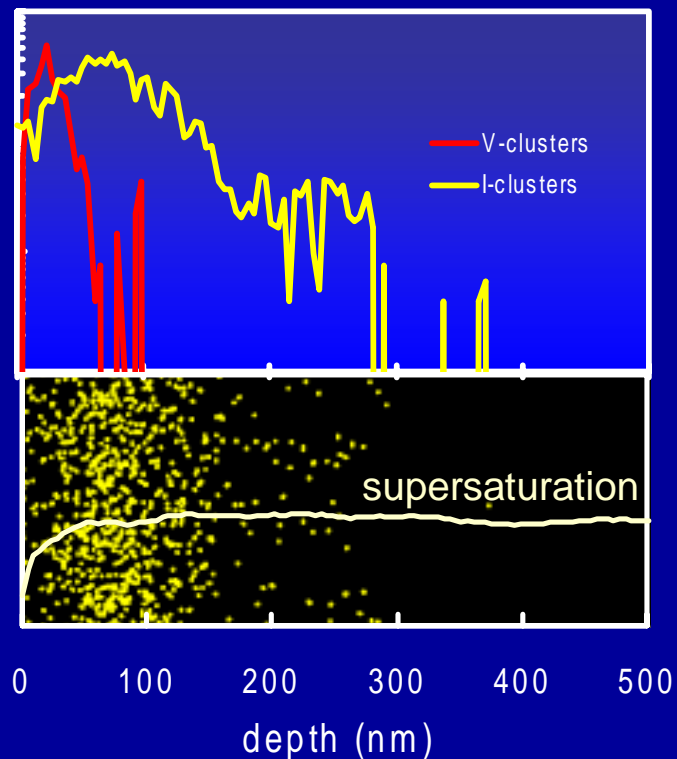
KMC used to validate simplifying assumptions

Emission energies of I-clusters:

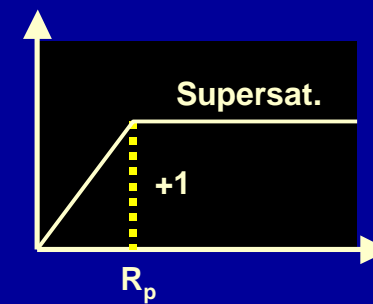
Cowern et al., Phys. Rev. Lett. 82, 4460 (1999)

Implant + Anneal

600 °C, 1000 s



Simplified model



- No V's (" +1 " model)

- ...

$$\frac{dN_n}{dt} = F_{n-1}N_{n-1} - F_nN_n - R_nN_n + R_{n+1}N_{n+1}$$

$$S = \frac{\sum_{n=2}^{\infty} \beta_n R_n N_n}{D_I C_I^* (\sum_{n=2}^{\infty} 4\pi a_n N_n + 1/r_p)}$$

where

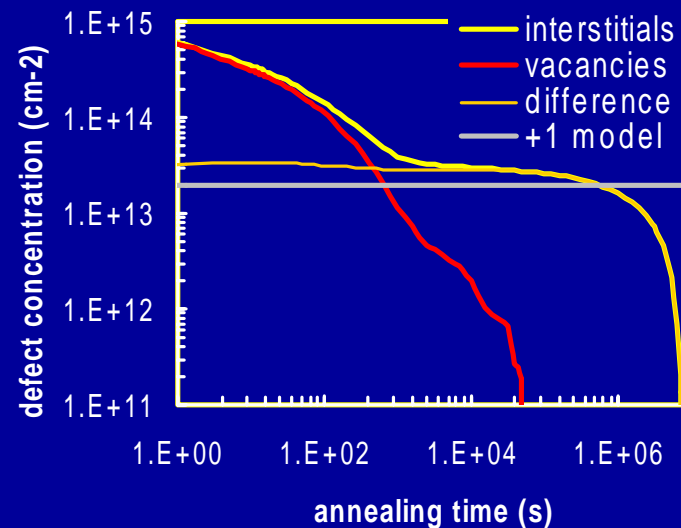
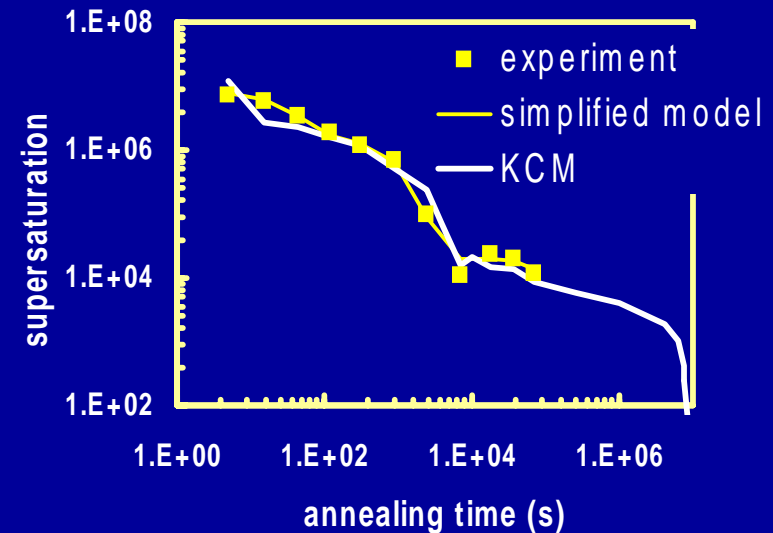
$$F_n = 4\pi a_n D_I C_I^* S,$$

$$R_n = (6D_{0n} a_n / \lambda^3) \exp -[E_{diss}(n)]/kT$$

How accurate is the Simplified model ?

- **Very good agreement with full simulation ...**

... in spite of the presence of Vacancies and other assumptions



KMC: Example 3

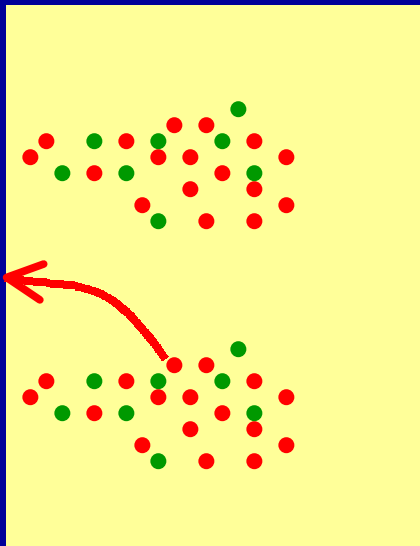
Implantation Damage and the
“+N” Number

KMC can yield an accurate “+N” :

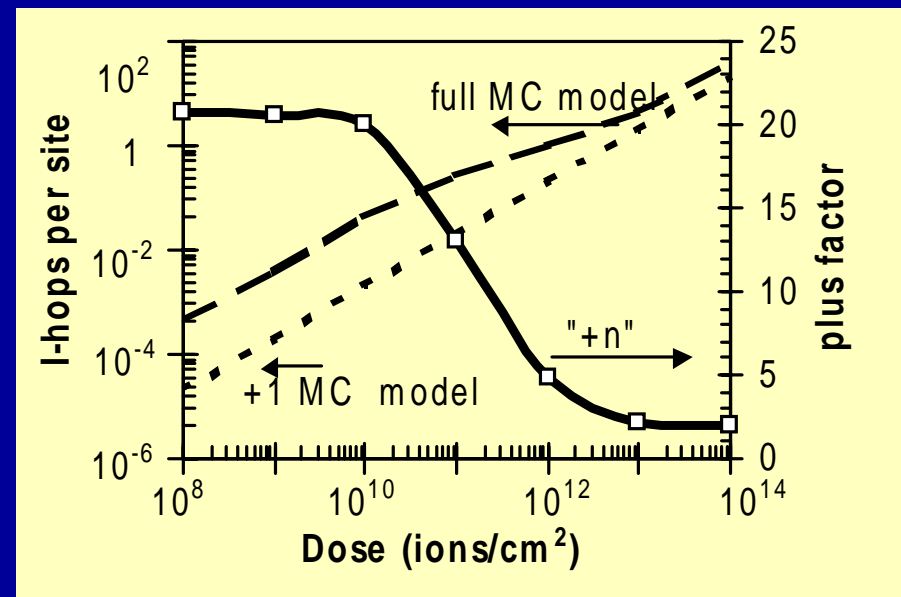
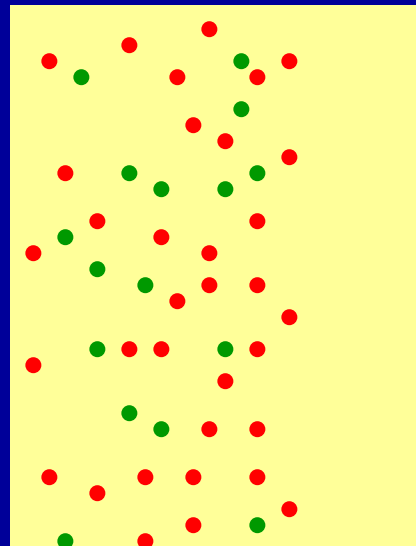
Low Dose Implant \longrightarrow

Non-overlapping Cascades
(Spatial Inhomogeneities)

Atomistic



Continuum



Pelaz et al., APL. 74 (1999) 2017



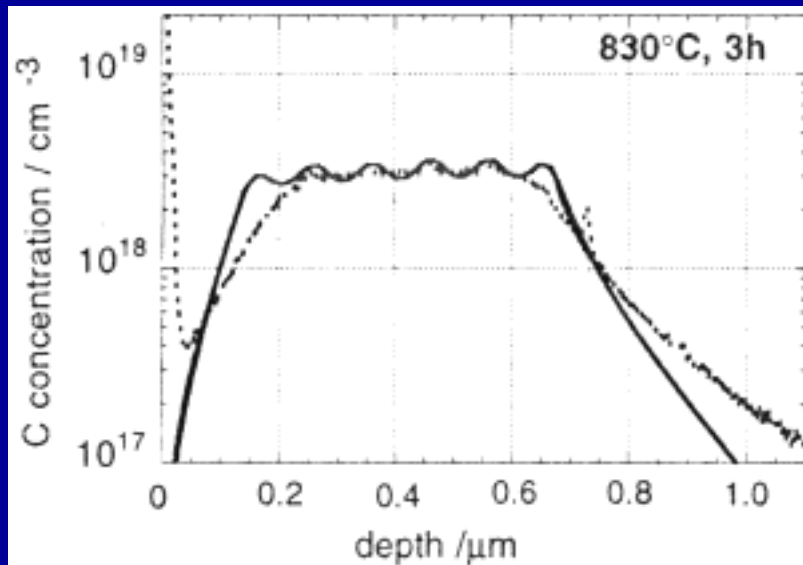
KMC: Example 4

Extraction of parameters for
Carbon diffusion in Silicon

Importance of Carbon in Silicon processing

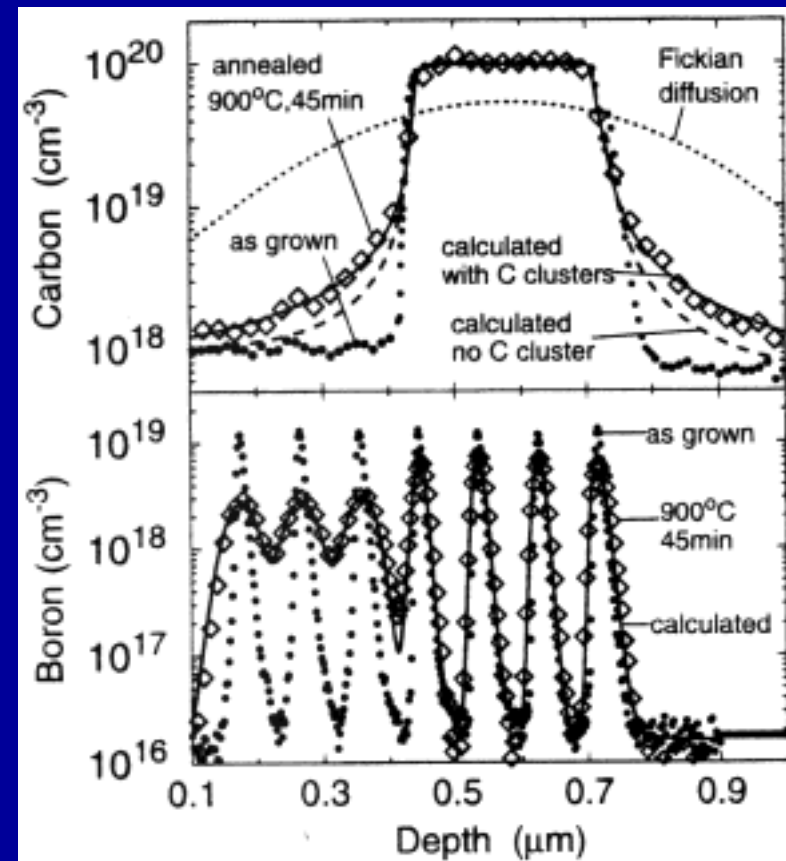
- Reduction of the diffusion of B and P
C traps self-Interstitials
- Unintentional impurity
Introduced during crystal growth.
- High concentration ($10^{16} - 10^{18} \text{cm}^{-3}$)
Above its solubility at annealing temperatures

Carbon diffusion: the state of the art

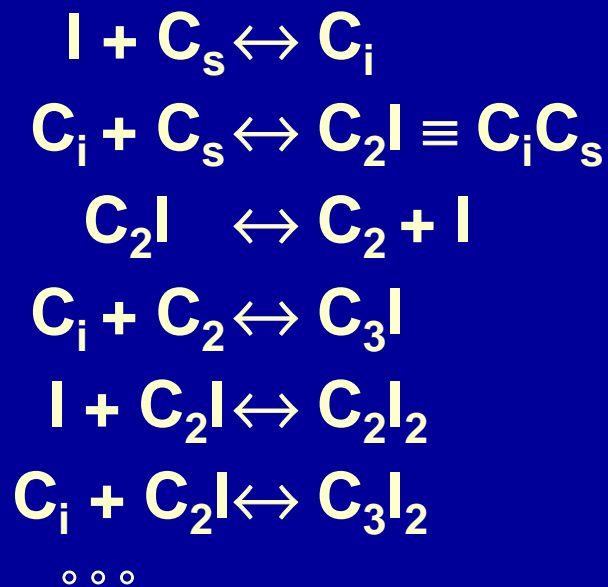


Werner et al., Appl. Phys. Lett. (1998)

*Rücker et al.
Appl. Phys. Lett. (1998)*



Improving the model with Carbon clustering mechanisms

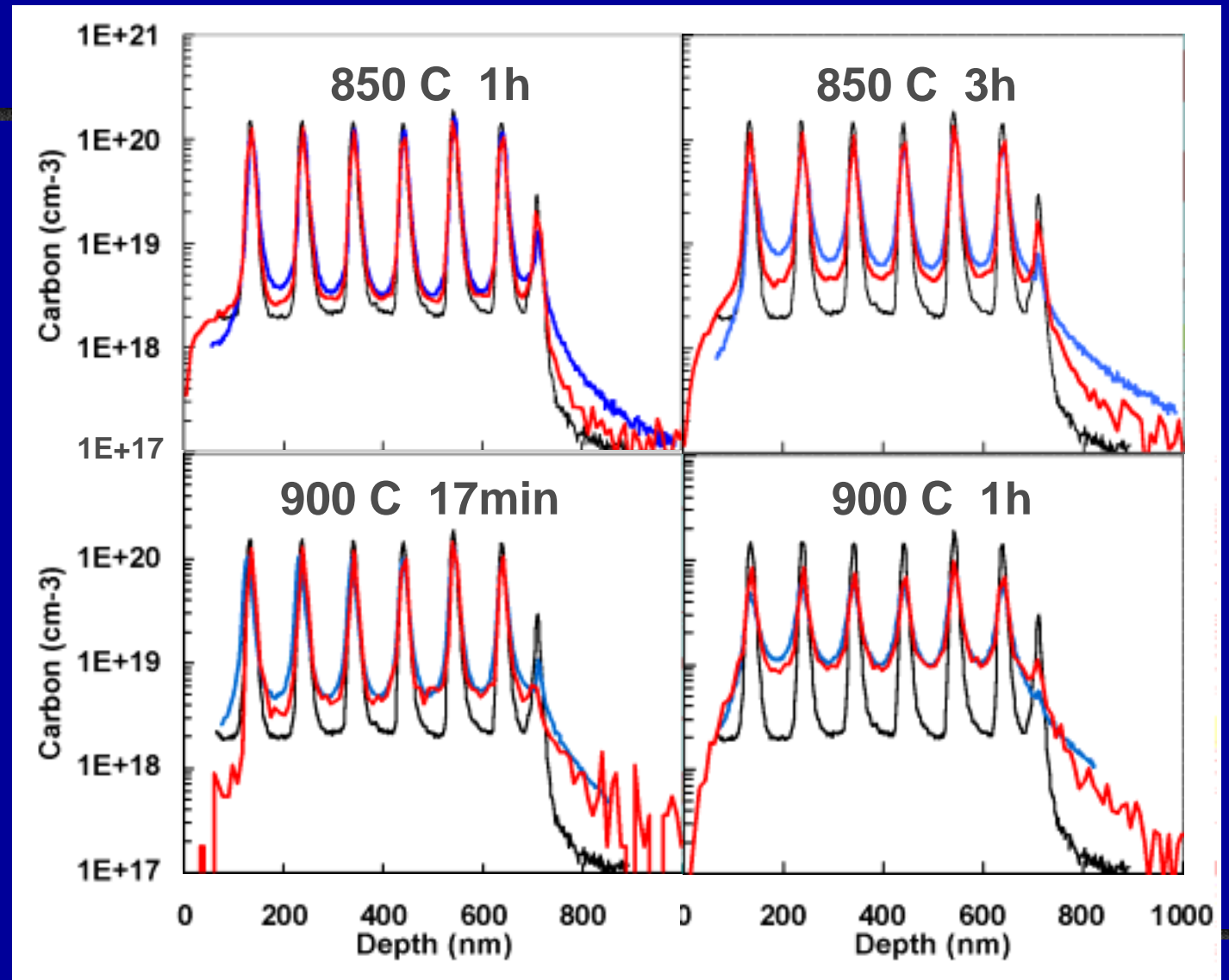
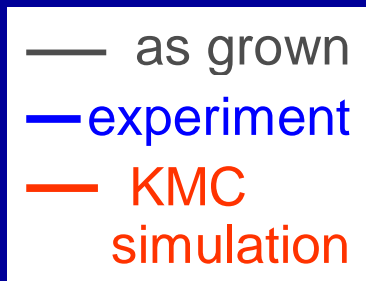


C	C ₂	C ₃	C ₄	...
CI \equiv C _i	C ₂ I	C ₃ I	C ₄ I	...
CI ₂	C ₂ I ₂	C ₃ I ₂	C ₄ I ₂	
CI ₃	C ₂ I ₃	C ₃ I ₃	C ₄ I ₃	
CI ₄	C ₂ I ₄	C ₃ I ₄	C ₄ I ₄	

...

- Continuum approach: many rate equations
- KCM: Easy modeling

KMC Simulation of Carbon diffusion



Pinacho et al.
MRS 2000

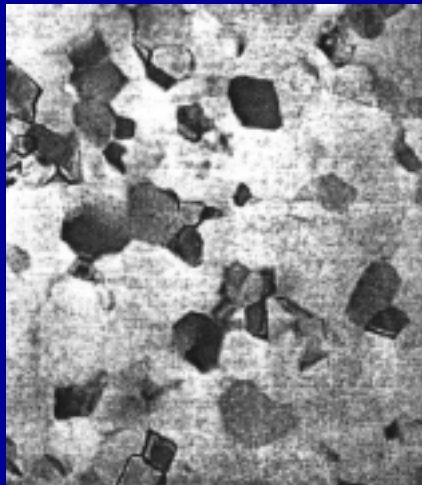


Lattice Kinetic Monte Carlo

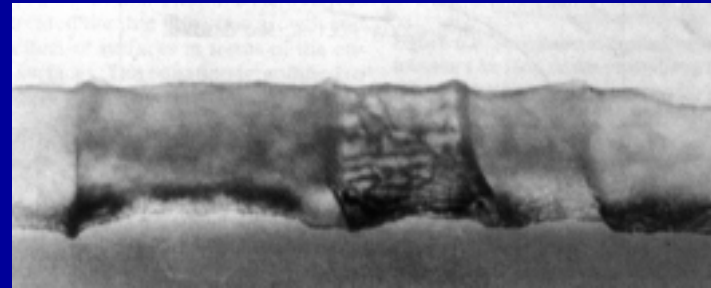
Polycrystalline Materials

Why Lattice KMC?

Aluminum, Polysilicon, ...: Polycrystalline structure



100 nm



0.5 μm

- Kang et al, J. Electron. Mater. , 1997
- Murarka, "Metallization", 1993

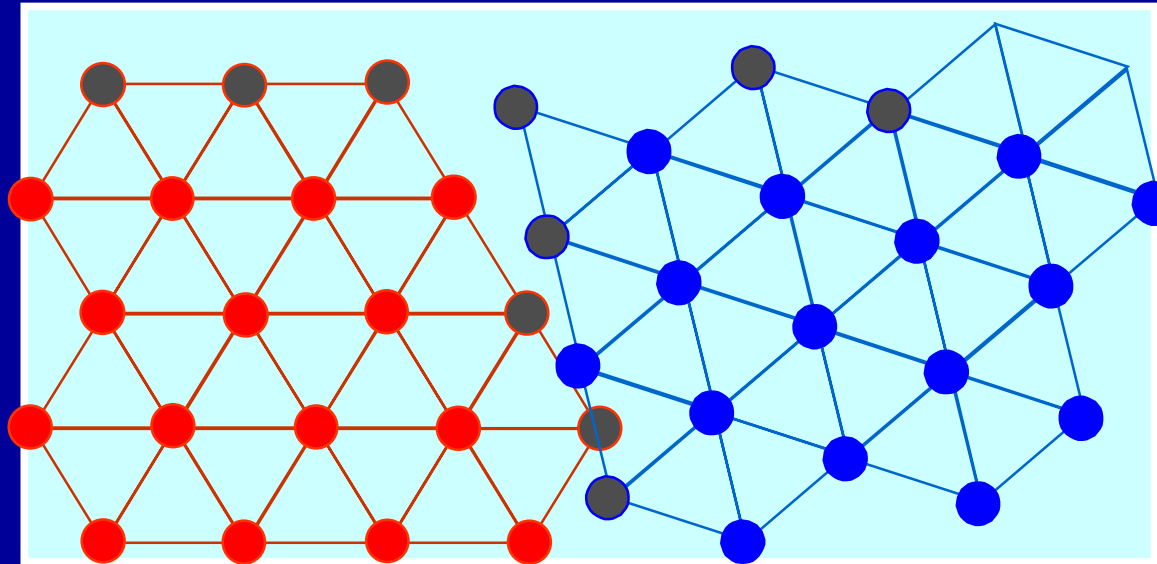
- Surface texture
- Grain Boundary diffusion
- Electromigration

Simulation approaches

- ↪ Continuum equations:
SPEEDIE, SAMPLE, EVOLVE, DEPICT
- ↪ 2-D ballistic simulator:
SIMBAD, GROFILMS
- ↪ 3-D atomistic approach: ADEPT

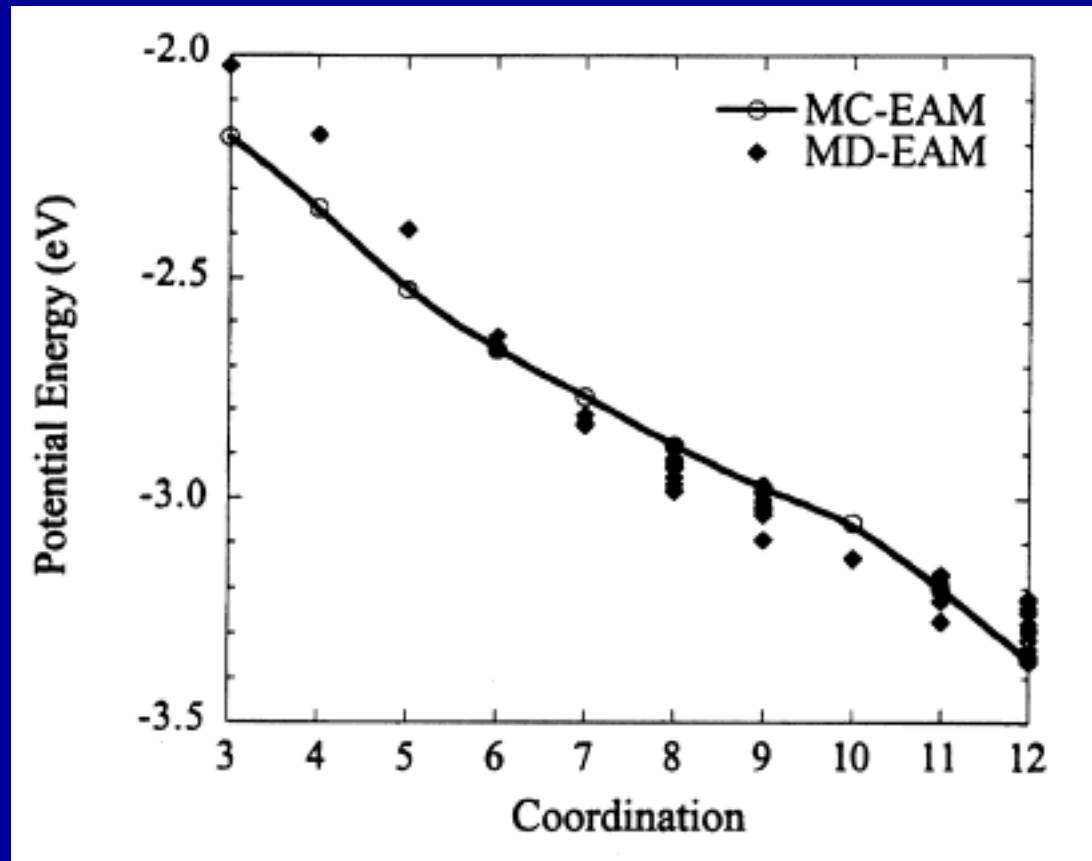
This Work: Polycrystalline 3-D atomistic approach

Simulation Box

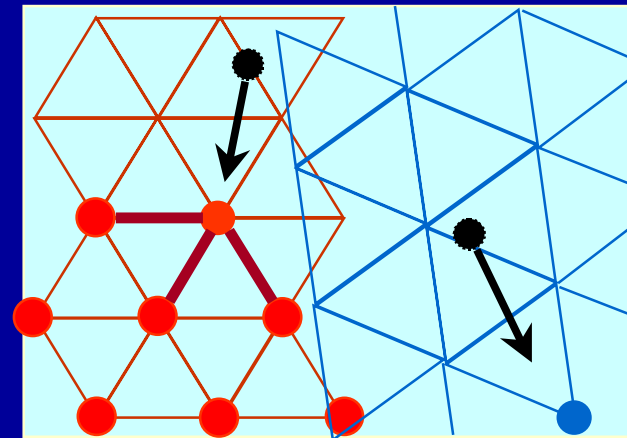
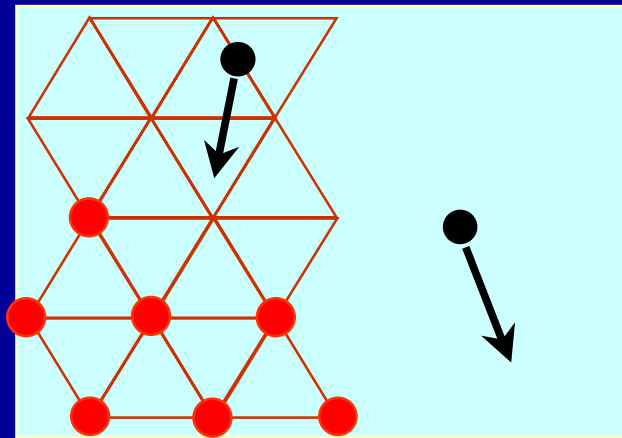


- Atoms are attached to the sites of a perfect fcc lattice.
- As a first approximation, the binding energy of each site depends on the number of occupied nearest neighbors

Energies from MD Embedded Atom Method using Gupta Potential

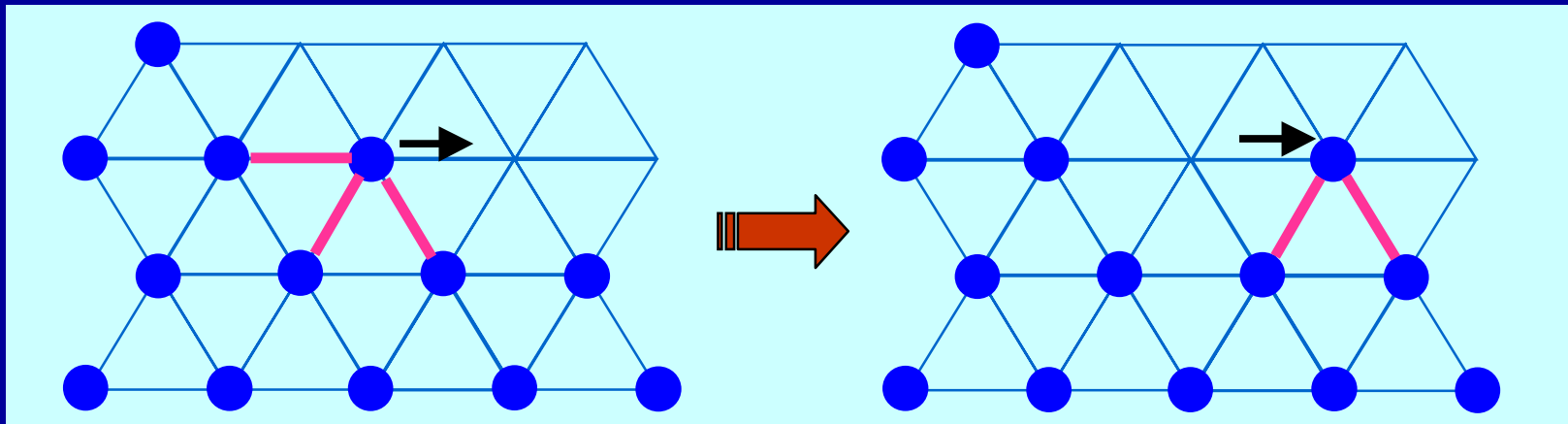


Deposition



- Initial position and velocity according to desired distribution
- Atom travels in a straight line until it either:
 - Finds some neighbors: gets attached to that grain
 - Finds no neighbors: starts a new grain (orientation).

Surface Diffusion

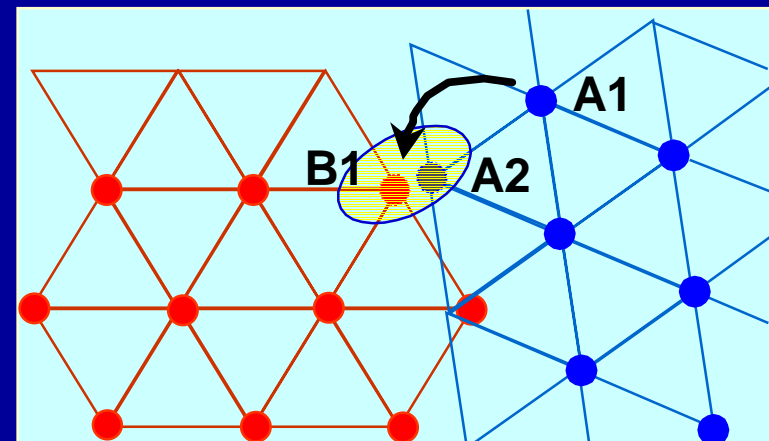
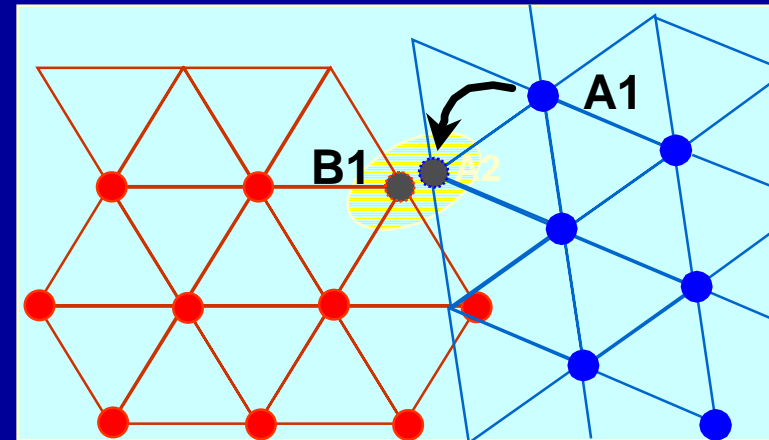


- Atoms not fully coordinated can jump to a neighboring empty site.
- The jump probability depends on the number of nearest neighbors and on the migration energy.

Grain Boundaries

If the destination site of a jump (A2) is at a grain boundary:

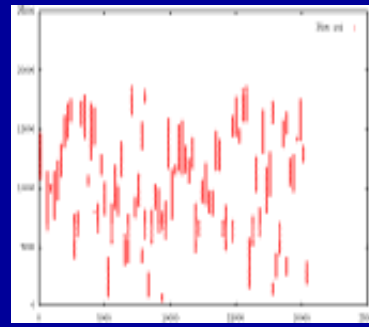
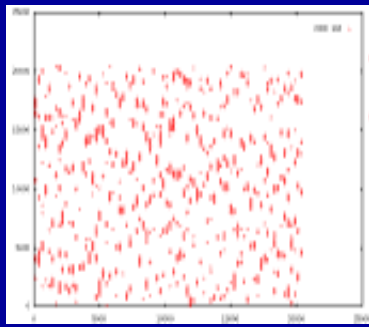
1. Check the energy of sites belonging to other orientations (B) around destination site.
2. If $\text{energy}(B1) < \text{energy}(A2)$ then the jump final site is B1.



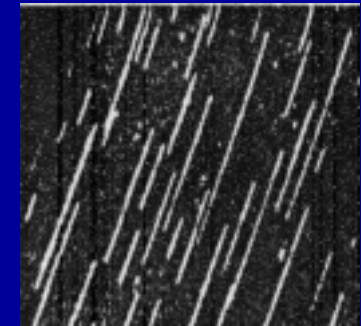
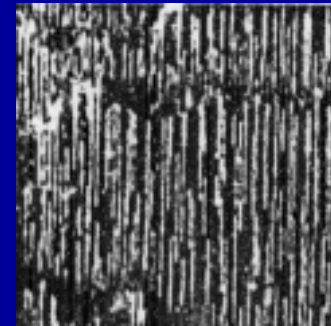
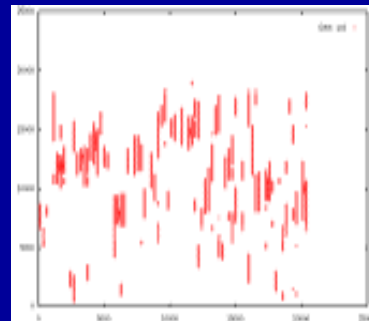
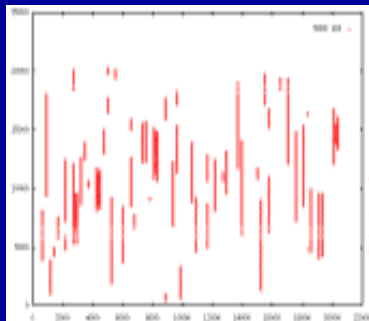
Lattice KMC: Simulation Examples

- Nucleation
 - Crystalline Substrates: Orientation
 - Amorphous Substrates: Wetting
- Annealing:
 - Texture evolution

Nucleation on Al (110)



10 nm



50 nm

STM images of Cu islands on Pd(100) at 265K and 300 K and coverage of 0.1 ML and 0.07 ML

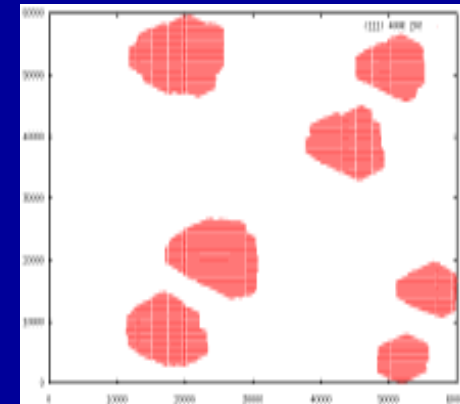
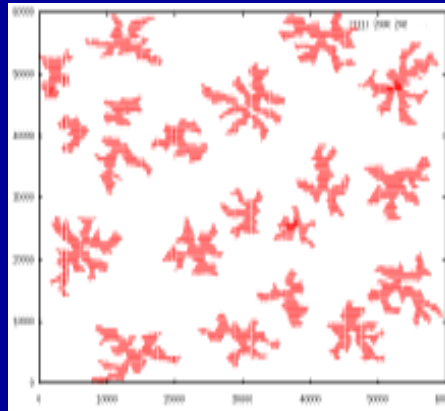
Simulation:

Al on Al (110) @ 200K, 350K, 500K, 600K

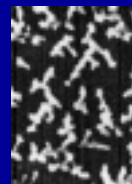
Coverage=0.1 ML

Nucleation on Al (111)

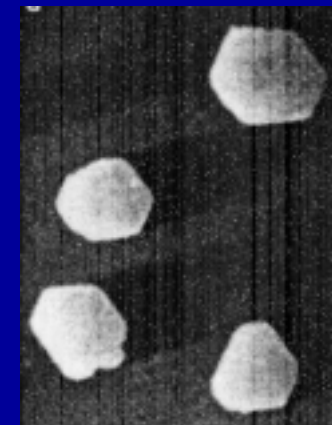
Simulation:
Al on Al (111)
@ 200K and 400K



STM measurements:
Pt on Pt(111)
@ 200K and 455K



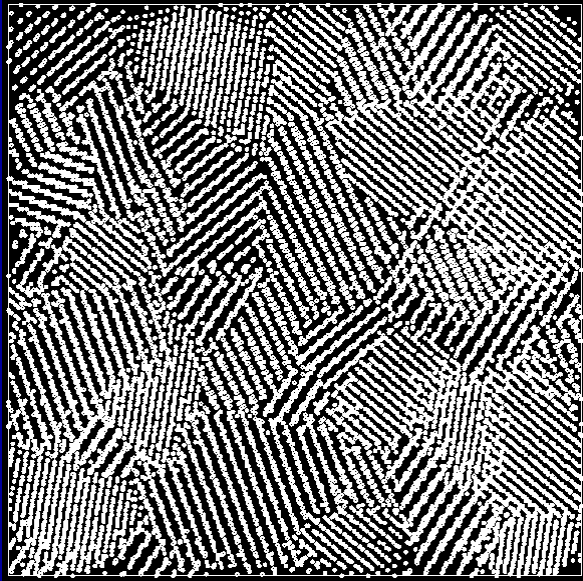
20 nm



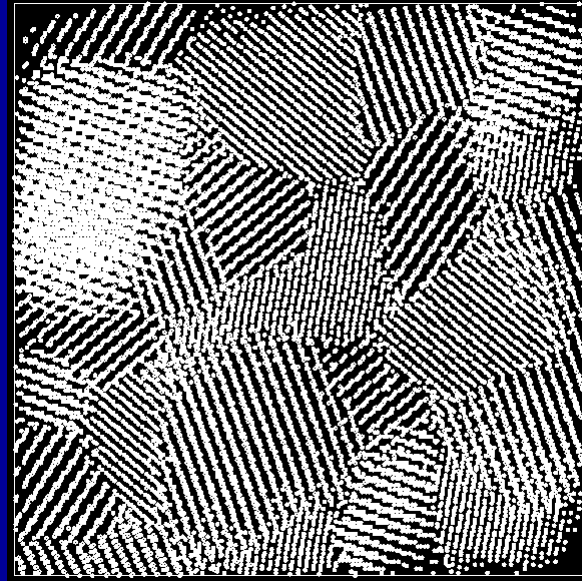
20 nm

Nucleation on Amorphous Substrates

Bonding to substrate: effect on the grain size



“Wetting” substrate
(Strong bonding)
=> smaller grains

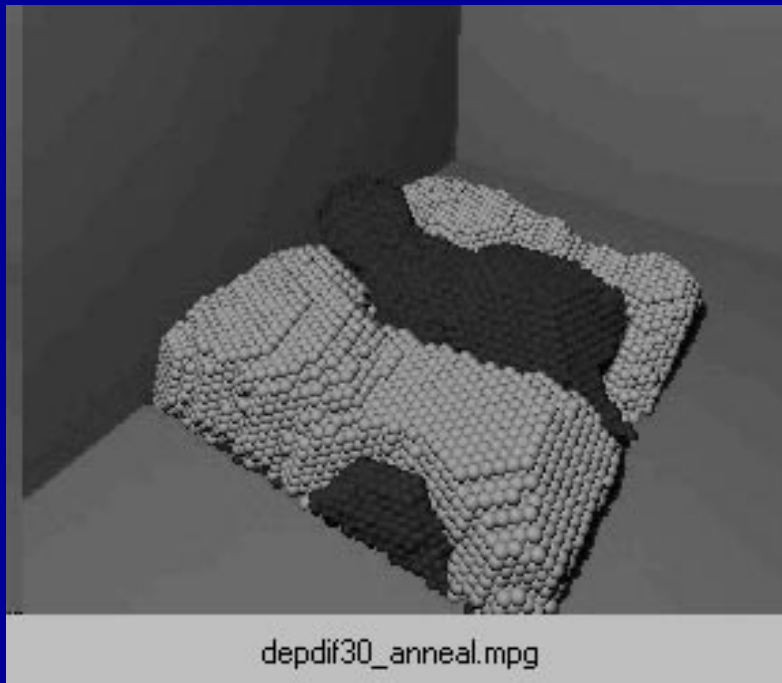


“Non-wetting” substrate
(Weak bonding)

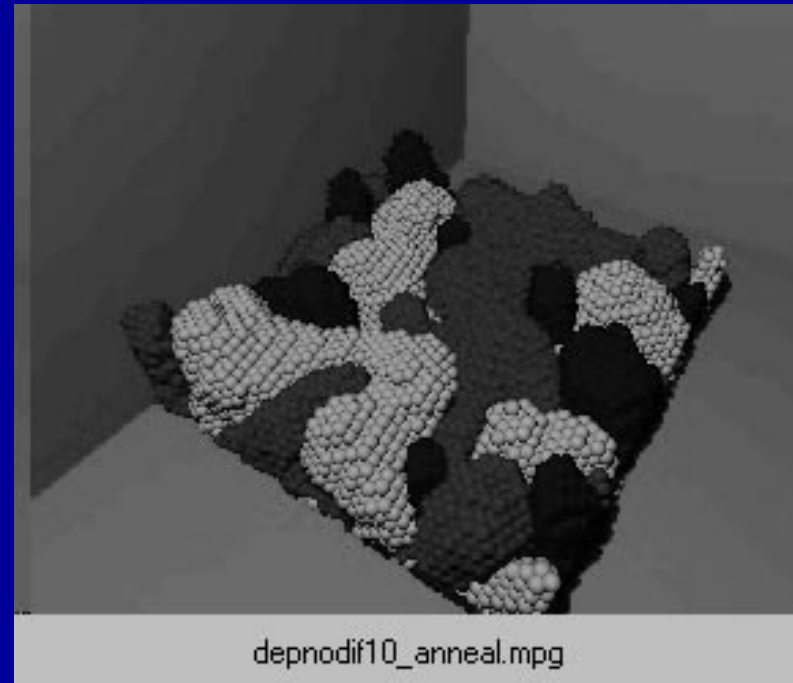
Annealing: Texture Evolution

Number of atoms: 20000
Simulation size: 0.012 μm
 \Rightarrow Actual size: 0.25 μm

$T_{\text{dep}} = T_{\text{ann}} = 663 \text{ K}$
Annealing time = 2.7 ms



$T_{\text{dep}} = T_{\text{ann}} = 513 \text{ K}$
Annealing time = 0.18 s





The Challenge

Obtaining KMC Input Parameters
In Complex Scenarios

Obtaining KMC Parameters from MD with a Genetic Algorithm

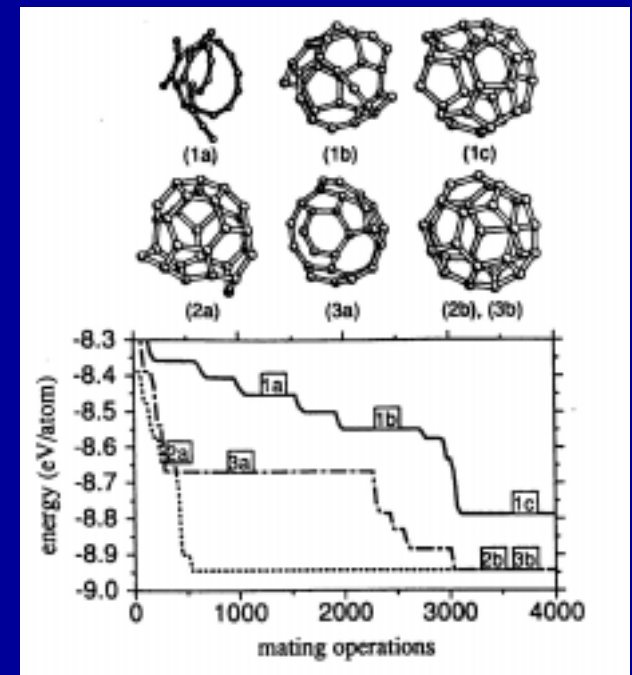
Problem: Find minimum energy configuration of 60 Carbon atoms, starting from random coordinates.

60 x 3 coords. = 180 unknowns

Assuming only 10 possible values for each coordinate: $\sim 10^{180}$ configs. ! (the Universe is about 10^{18} s old)

- The GA found the solution in ~ 5000 steps (configs.)
- It had not been solved by any other technique before

Free-standing Si clusters: Ho et al., *Nature* **392** (1998) 582



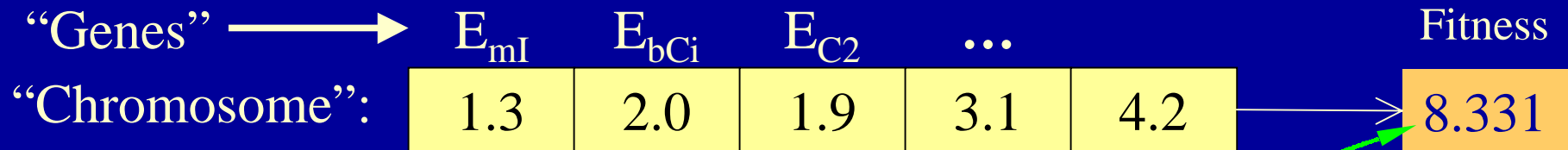
Deaven and Ho, PRL **75** (1995) 288

Evolutionary Computation (Genetic Algorithms, ...)

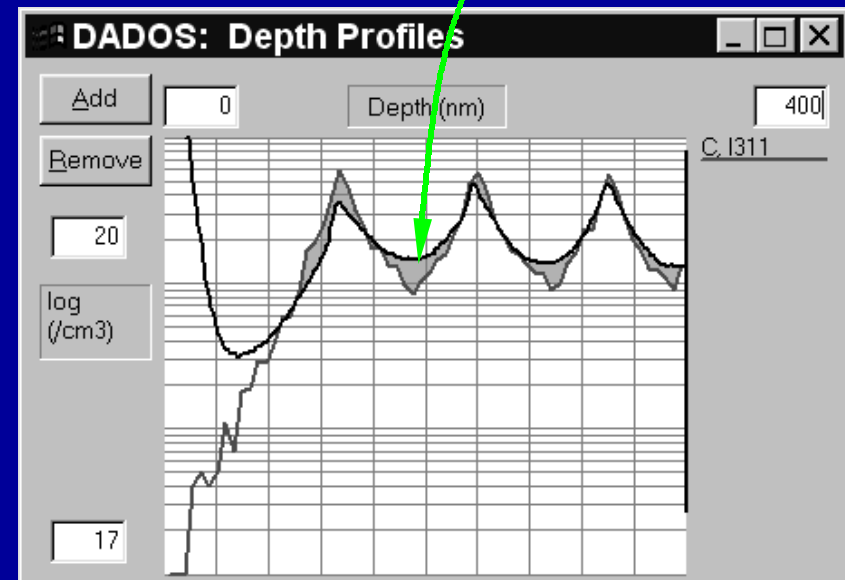
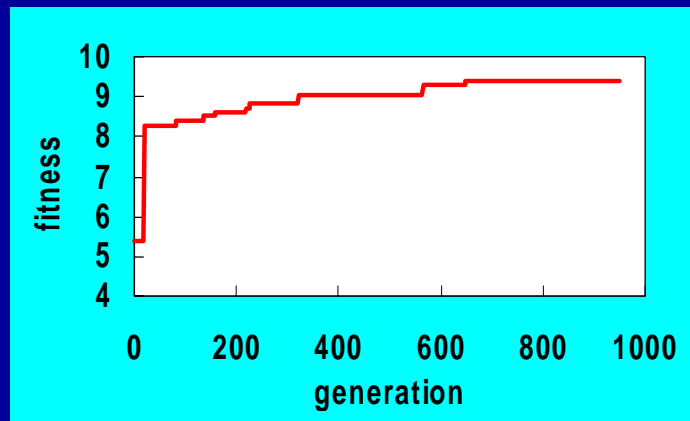
D. B. Fogel, IEEE Spectrum, Feb. 2000:

- “... is one of the fastest growing areas of Computer Science”
- “It is addressing **complex engineering** problems that were previously beyond reach”

Using a GA To Extract KMC Parameters From Experimental Data

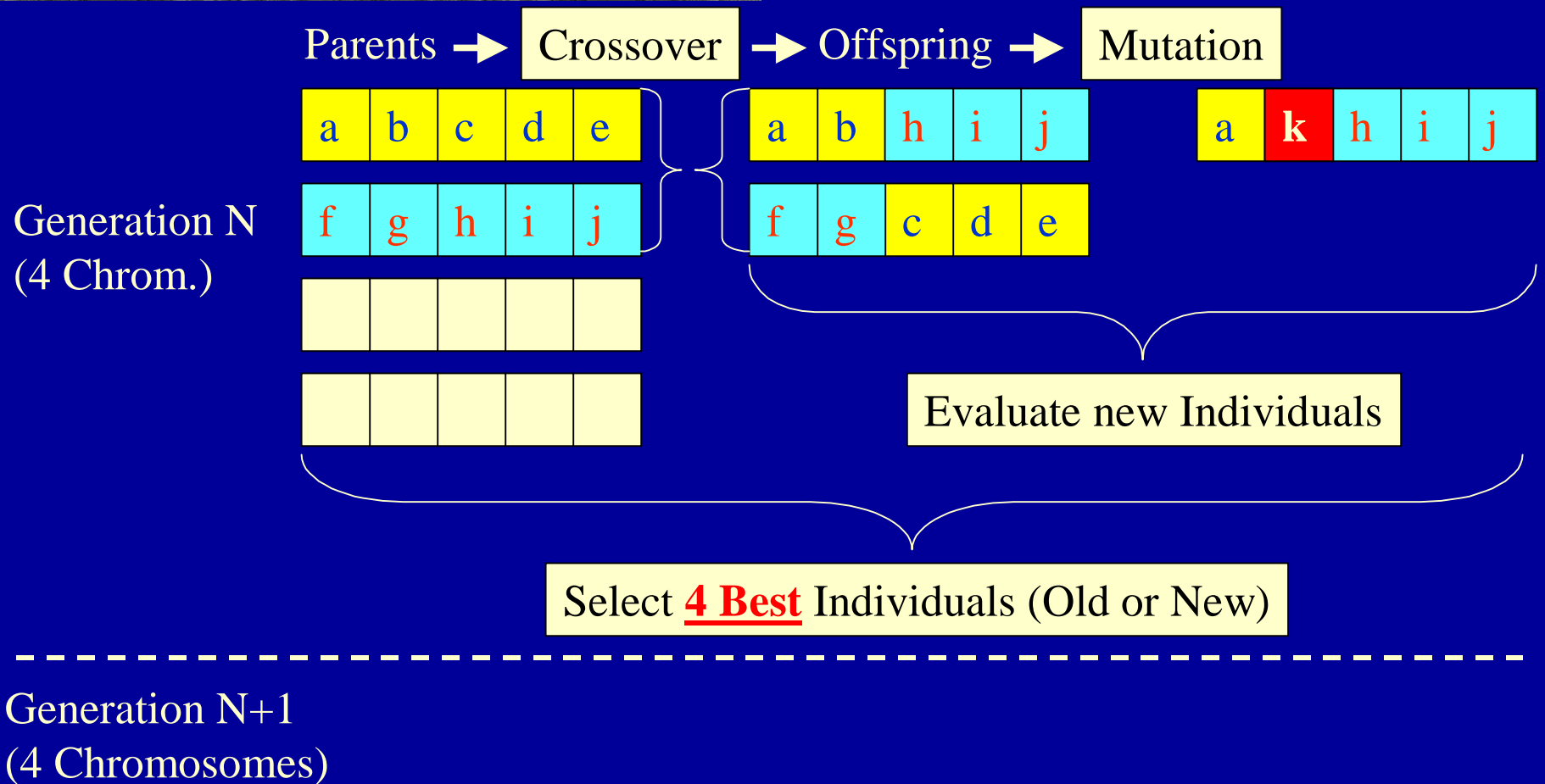


Fitness Evaluation: DADOS simulations
(just a rough estimate)
done in ~ 3 minutes / simulation



Genetic Algorithm from: <http://lancet.mit.edu/ga/>

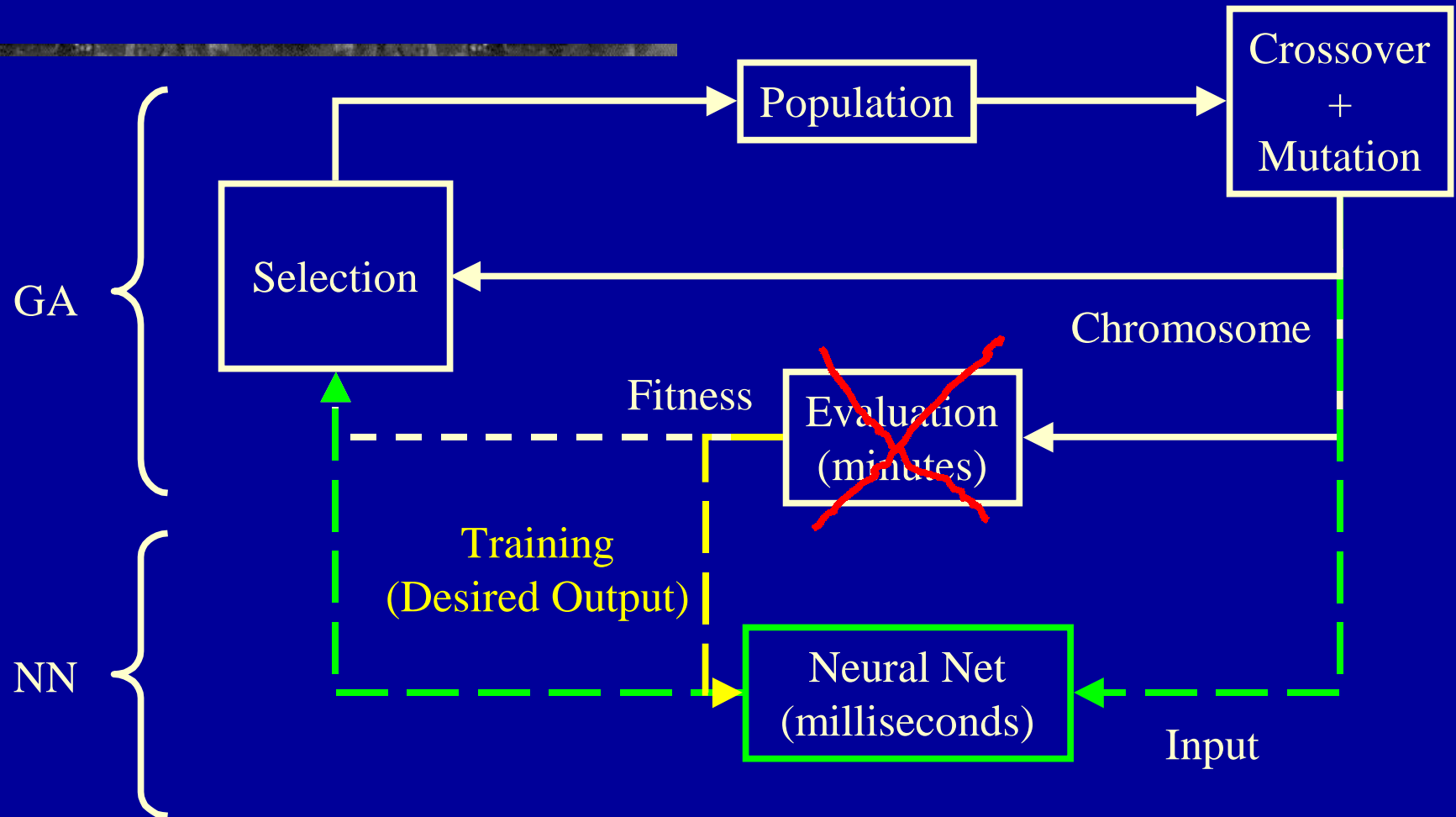
What Is a Genetic Algorithm?





Looking Ahead

Looking Ahead: GA + Neural Networks



Looking Ahead

- Genetic Programming

- Symbolic Regression:

- Set of symbols: { +, -, /, •, exp, cos, X, Y, Z, ... }

- Find best fitting **function**: $f = X - Z \cdot \exp(Y)$

- Materials Processing:

- Set of mechanisms: { Frank-Turnbull,
Interstitialcy, Surface emission, E_1 , E_2 , ... }

- Find best mechanisms and energies

- ...

In Summary:

Materials Research can benefit from:

- Atomistic KMC Process Modeling
 - Detailed and Accurate
 - Straightforward to Implement / Modify new Models
 - Can handle complex Processing scenarios
- AI methods (Genetic Algorithms, Neural Nets, ...)
 - Opening a whole new range of capabilities
 - Currently under intense exploration. Looks most promising